

Si4822DY

Single N-Channel, Logic Level, PowerTrench MOSFET

GeneralDescription

This N-Channel Logic Level MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

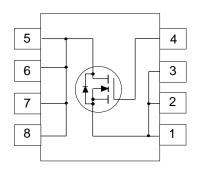
These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

Features

- Fast switching speed.
- Low gate charge.
- High performance trench technology for extremely low R_{DS(ON)}.
- High power and current handling capability.







Absolute Maximum Ratings $T_A = 25^{\circ}C$ unless other wise noted

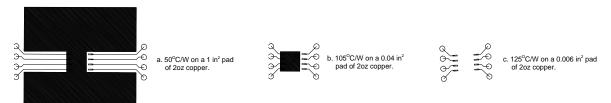
Symbol	Parameter	Si4822DY		
/ _{DSS}	Drain-Source Voltage	30	V	
V _{GSS}	Gate-Source Voltage	±20	V	
D	Drain Current - Continuous (Note 1a)	12.5	A	
	- Pulsed	50		
P_{D}	Power Dissipation for Single Operation (Note 1a)	2.5	W	
	(Note 1b)	1.2		
	(Note 1c)	1		
T_J , T_{STG}	Operating and Storage Temperature Range	-55 to 150	°C	
THERMA	L CHARACTERISTICS			
R _{OJA}	Thermal Resistance, Junction-to-Ambient (Note 1a)	50	°C/W	
₹ _{øJC}	Thermal Resistance, Junction-to-Case (Note 1)	25	°C/W	

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Symbol	Characteristics (T _A = 25 °C unless otherwise) Parameter	Conditions		Min	Тур	Max	Units
	ACTERISTICS	Conditions			יאף	IVICIA	Office
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		30			V
	Breakdown Voltage Temp. Coefficient	$V_{GS} = 0 \text{ V}, V_D = 250 \mu\text{A}$ $I_D = 250 \mu\text{A}, \text{ Referenced to } 25 ^{\circ}\text{C}$		30	33		mV/°C
$\Delta BV_{DSS}/\Delta T_{J}$		5 .			33		
DSS	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \ V_{GS} = 0 \text{ V}$	T 5500			1	μA
		.,	$T_J = 55^{\circ}C$			10	μΑ
GSSF	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
GSSR	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHARAC	CTERISTICS (Note 2)			ı	1	_	
$\Delta V_{\text{GS(th)}}\!/\!\Delta T_{\text{J}}$	Gate Threshold Voltage Temp. Coefficient	$I_D = 250 \mu\text{A}$, Referenced to	to 25 °C		-4.5		mV /°C
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	-	1	1.6	3	V
			T _J =125°C	0.8	1.3	2.4	
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 12.5 \text{ A}$			0.008	0.0095	Ω
			T _J =125°C		0.012	0.016	
		$V_{GS} = 4.5 \text{ V}, I_{D} = 10.5 \text{ A}$			0.0105	0.013	
I _{D(ON)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, \ V_{DS} = 5 \text{ V}$		25			Α
g _{FS}	Forward Transconductance	$V_{DS} = 15 \text{ V}, I_{D} = 12.5 \text{ A}$			35		S
DYNAMIC C	HARACTERISTICS			·			
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			2180		pF
Coss	Output Capacitance				500		pF
C _{rss}	Reverse Transfer Capacitance				255		pF
SWITCHING	CHARACTERISTICS (Note 2)						
t _{D(on)}	Turn - On Delay Time	V _{DS} = 10 V, I _D = 1 A			13	24	ns
t,	Turn - On Rise Time	$V_{GS} = 10 \text{ V}$, $R_{GEN} = 6 \Omega$			14	26	ns
$t_{D(off)}$	Turn - Off Delay Time				43	70	ns
t _r	Turn - Off Fall Time				15	27	ns
$\overline{Q_g}$	Total Gate Charge	$V_{DS} = 15 \text{ V}, I_{D} = 12.5 \text{ A},$			23	33	nC
Q_{gs}	Gate-Source Charge	V _{GS} = 5 V			7		nC
$\overline{Q_{gd}}$	Gate-Drain Charge				11		nC
DRAIN-SOU	RCE DIODE CHARACTERISTICS AND MAXIMU	JM RATINGS		•	•		•
I _s	Maximum Continuous Drain-Source Diode Fo	rward Current				2.1	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 2.1 \text{ A}$ (Note	e 2)		0.72	1.2	V
		•		•	•	•	•

Notes

^{1.} $R_{g,h}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{g,C}$ is guaranteed by design while $R_{g,C,h}$ is determined by the user's board design.



Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width $\leq 300 \mu s,$ Duty Cycle $\leq 2.0 \%.$

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Typical Electrical Characteristics

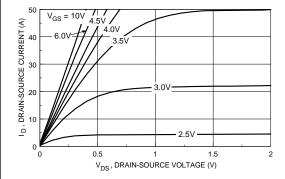


Figure 1. On-Region Characteristics.

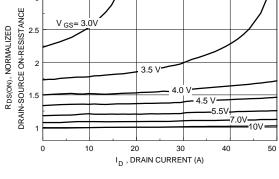


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

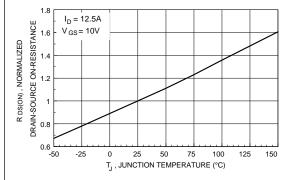


Figure 3. On-Resistance Variation with Temperature.

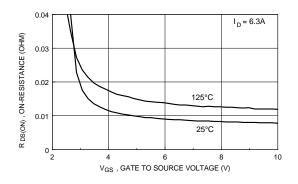


Figure 4 . On Resistance Variation with Gate-to-Source Voltage.

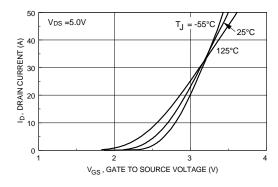


Figure 5. Transfer Characteristics.

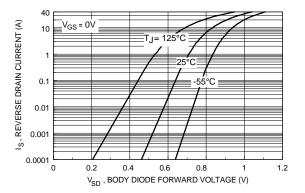


Figure 6 . Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Electrical And Thermal Characteristics

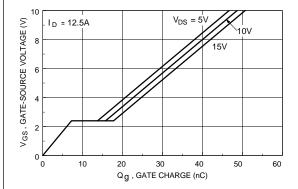


Figure 7. Gate Charge Characteristics.

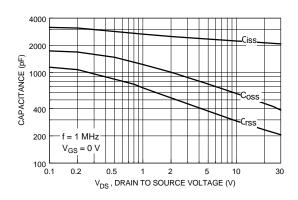


Figure 8. Capacitance Characteristics.

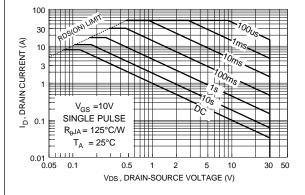


Figure 9. Maximum Safe Operating Area.

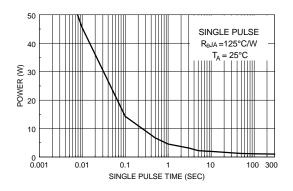


Figure 10. Single Pulse Maximum Power Dissipation.

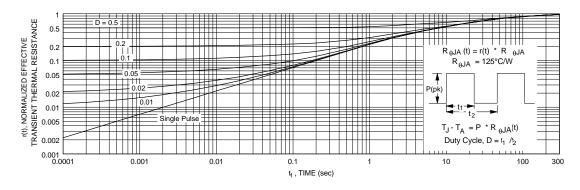


Figure 11. Transient Thermal Response Curve .

Thermal characterization performed using the conditions described in Note 1c.

Transient thermal response will change depending on the circuit board design.

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